

## ENEA and Taylor Hobson invite you for a Non-contact Metrology Seminar

ENEA, April 15th, from 9:45 a.m. - 4:00 p.m.

Piazzale Enrico Fermi, 1 - Località Granatello - 80055 Portici (NA)

### PROGRAMME

9:45 - 12:30

Dr. Ezio Terzini

General introduction to ENEA

Fabio Papaleo

General introduction to Taylor Hobson

Dr. Mike Conroy

Introduction to interferometry

- How it works
- Strengths / Weaknesses

13:30 - 16:00

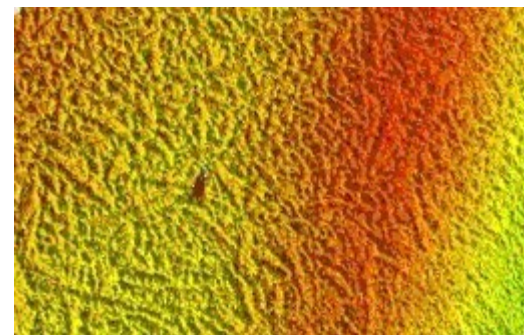
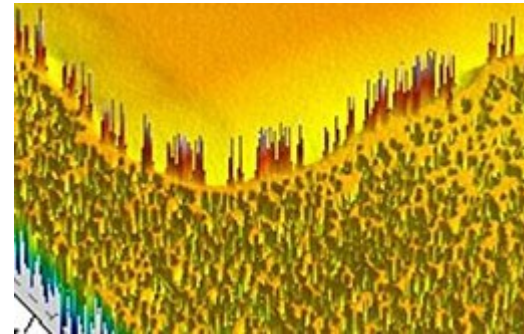
Dr. Mike Conroy

Introduction to CCI

- How it works
- Coating measurements

Applications

- Optics
- Micro-electronics
- Coatings
- Others
- Correlation between contact and non-contact techniques.



Taylor Hobson experts in non-contact metrology will be available for personal consultation on your most complex measurement requirements

Taylor Hobson is an ultra-precision technology company operating at the highest levels of accuracy within the field of surface, roundness and form metrology, providing contact and non-contact measurement solutions for the most demanding applications.

For more information please contact Valter Brambilla : [valter.brambilla@ametek.it](mailto:valter.brambilla@ametek.it)  
Fabio Papaleo: [papaleo.f@rimec.net](mailto:papaleo.f@rimec.net)



Italian national agency for new technologies,  
energy and sustainable economic development

ENEA UTTP-NANO ("Laboratory of Nanomaterials and Devices") is part of the Technical Unit Portici Technologies (UTTP) located in Portici, near Naples (Italy). Its research activities are focused on the design, fabrication and characterization of OLEDs (Organic Light-Emitting Diodes), OTFTs (Organic Thin-Film Transistors) and OPV (Organic Photovoltaic cells) starting from the idea of the single device up to its test and performance parameters extraction.

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